

M5500, M5515, M5516 M5622, M5623

FULL SIZE D.I.L. M package

HALF SIZE D.I.L. H package H5622, H5623

# Thru-Hole

# HIGH RELIABILITY 1 Hz to 125 MHz

MF Electronics oscillators are not compliant with MIL-PRF-55310

#### **FEATURES**

- · Hermetically sealed half size or full size DIL package
- Crystal angle controlled to ±1 minute for excellent temperature stability
- 168 hour Class B burn-in and extensive environmental testing for best performance in rugged field environments
- · Start-up time less than 10 ms
- · Serialized test data available

## TYPICAL APPLICATIONS

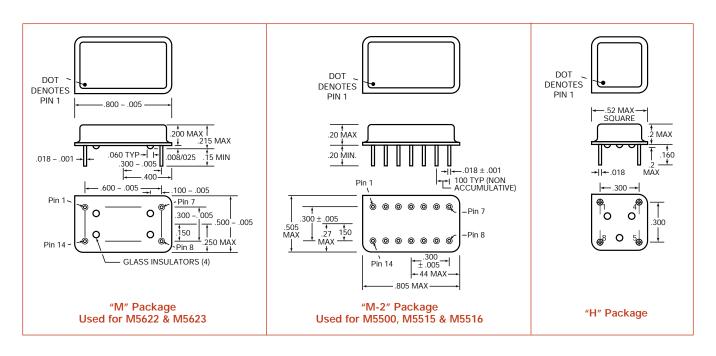
• Thru-hole PCB projects requiring high reliability HCMOS clock waveforms

Full Size		Half Size		Operating	
Model	Package	Model	Package	Temperature	Frequency Stability
M5500, M5516	M-2			-55 to +125°C	±75 ppm
M5515	M-2			0 to 70°C	±50 ppm
M5622	М	H5622	Н	-55 to +85°C	±50 ppm
M5623	М	H5623	Н	-55 to +125°C	±75 ppm

The M5500 is a 14-pin device with case ground on Pin 1, while the M5515 and M5516 have case ground on Pin 7.

# Description

These high reliability oscillators provide HCMOS clock waveforms for applications subjected to the most stringent environmental conditions. The full size models can be provided in packages with 4 pins, or 14 pins for extra holdability.







CRYSTAL OSCILLATORS HCMOS 5V

Thru-Hole

# HIGH RELIABILITYS FIXED FREQUENCY, 1 Hz to 125 MHz

FULL SIZE D.I.L. M package M5500, M5515, M5516 M5622, M5623

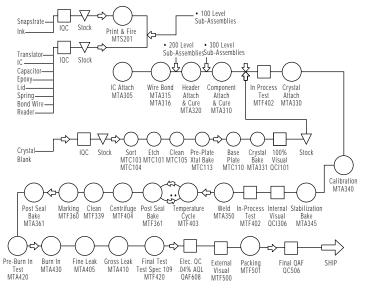
HALF SIZE D.I.L. H package H5622, H5623

## CONNECTIONS, FULL SIZE PACKAGE

Pin	M5500	M5515, M5516	M5622, M5623	
1.	Case	N.C.	Case & Electrical Ground	
2.	N.C.	N.C.	Pins	
3.	N.C.	N.C.	2 thru 6	
4.	N.C.	N.C.	are not	
5.	N.C.	N.C.	present	
6.	N.C.	N.C.	present	
7.	Electrical Ground	Case & Electrical Ground	Case & Electrical Ground	
8.	Output	Output	Output	
9.	N.C.	N.C.	Pins	
10.	N.C.	N.C.	9 thru 13	
11.	N.C.	N.C.	are not present	
12.	N.C.	N.C.		
13.	N.C.	N.C.	prosent	
14.	+5V, V <sub>DD</sub>	+5V, V <sub>DD</sub>	+5V, V <sub>DD</sub>	

### CONNECTIONS

	Half Size
	Not Used
Pin 4.	Ground and Case
Pin 5.	Output
Pin 8.	+5V, V <sub>DD</sub>



NOTE: • Indicates where Sub-Contracted Assemblies and Sub-Assemblies enter the Manufacturing line.

All Sub-Contracted Assemblies and Sub-Assemblies are inspected to QCl307 and stored in stock until needed.

•• Indicates Post Seal Bake and Temperature Cycle Processes may be performed in reverse order.

# **ELECTRICAL SPECIFICATIONS**

### Frequency Range

M5500, M5515, M5516, M5622, M5623 – 1 Hz to 125 MHz H5622, H5623 – 1 KHz to 125 MHz

Frequency Stability Includes calibration at 25°C, operating temperature, change of input voltage, change of load, shock and vibration.

	MIN	TYP	MAX	UNITS
Input Voltage	4.5	5.0	5.5	volts
Input Current				
Frequency at 1 KHz or above		30	55	mA
Frequency below 1 KHz		35	60	mA
Frequency Accuracy	See preceding Table			
Waveform Symmetry,				
Measured at 1.5V	40/60		60/40	percent
Rise and Fall Times				
Below 10 MHz		_		
0.8 to 2.4 volts		5	15	ns
10 MHz and above,		0	F	
0.8 to 2.4 volts		2	5	ns
"Zero" Level,			0.5	
Sinking 16 mA			0.5	volts
"One" Level				
Sourcing 400 microAmps	4.5 2.5			volts
Sourcing to 10 TTL loads	2.5			volts
Frequency Change from +4.5 to +5.5V		+5		ppm
Aging				1.1.
First year		3		ppm
After first year		1		ppm/yr

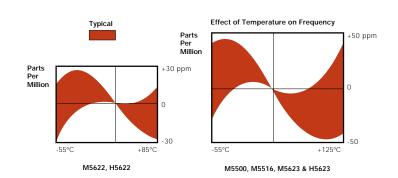
### **ENVIRONMENTAL SPECIFICATIONS**

**Temperature Cycle** – Not to exceed  $\pm 5$  ppm change when exposed to 2 hours maximum at each temperature from 0 to 120°C, with 25°C reference.

Shock – 1000 Gs, 0.35 ms, 1/2 sine wave, 3 shocks in each plane

Vibration - 10-2000 Hz of .06" d.a. or 20 Gs, whichever is less

Humidity - Resistant to 85° R.H. at 85°C







CRYSTAL OSCILLATORS HCMOS 5V

Thru-Hole

# HIGH RELIABILITY FIXED FREQUENCY, 1 Hz to 125 MHz

FULL SIZE D.I.L. M package M5500, M5515, M5516 M5622, M5623

HALF SIZE D.I.L. H package H5622, H5623

### **MECHANICAL DESCRIPTION**

Case - Stainless Steel

Marking – MF part number, date code, serial number and description Marking will withstand MIL-STD 202, Method 215

Optional Marking - Customer part number if required

Leads - Kovar, nickel plated, gold flash

Shock - MIL-STD 202, Method 213A, Test Condition 1

Vibration: - MIL-STD 202, Method 204B, Test Condition B

## Each unit undergoes the following:

Stabilization Bake
 Temperature Cycling
 Centrifuge
 Fine Leak
 Gross Leak
 Temperature Cycling
 MIL-STD-883 Method 1010, Cond. B
 MIL-STD-883 Method 2001, Cond. A
 MIL-STD-883 Method 1014, Cond. A1
 MIL-STD-883 Method 1014, Cond. C
 Within ±75 ppm from -55 to +125°C

(M5500, M5516, M5623, H5623) Within ±50 ppm from -55 to +85°C

(M5622 and H5622)

7. Electrical Test at 25°C, as follows:

## TABLE 1

A. Frequency
B. Current
C. Rise Time (NL)
D. Fall Time (NL)

H. Duty Cycle (FL)
I. Frequency at 5.5V
J. Frequency at 4.5V
K. Overvoltage

(6.5 volts for 30 seconds)

E. Rise Time (FL)

L. "Zero" logic level

F. Fall Time (FL)

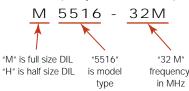
M. "One" logic level

G. Duty Cycle (NL)

Test data on each unit is available for additional cost

# **HOW TO ORDER**

For Part Number, put package type before model number, and add frequency in MHz, for example:



# TABLE 2 — RELIABILITY TEST PROCEDURE AND CONDITIONS FOR QUARTZ CRYSTAL OSCILLATORS

# I. Group A

Electrical Characteristics at 0, 25, 70 and 125°C

Frequency @ 4.5, 5.0 and 5.5 volts (for 5 volts units)

Symmetry (Duty Cycle)

Input current

Zero/One levels

Rise/Fall times

Physical Dimensions

Length/width

Height

Glass seal (Visual)

Package finish (Corrosion, discoloration, etc.)

Marking placement/legibility

#### II. Group B

1000 hrs aging at or above 70°C, 5.0V VDC, with proper load

# III. Group C - All units have passed Group A testing

### A. Subgroup 1 - 8 pcs.

MIL-STD-883 METHOD 1014

MII -STD-883

COND. B

COND. C

METHOD 1014

Standard MIL-STD-883	Condition METHOD 2002 COND. B	Description Mechanical shock 1500 g's, 5ms 5 drops, 6 axis	End point measurement Frequency Output waveform		
MIL-STD-883	METHOD 2007 COND. A	Vibration, var. freq. 20 g's, .06" disp., 20- 20,000-20 Hz	Frequency Output waveform		
MIL-STD-883	METHOD 2003	Solderability	Visual 95% coverage		
B. Subgrou	p 2 - 4 pcs (One-ha	olf of Subgroup 1)			
MIL-STD-883	METHOD 1011 COND. B	Thermal Shock Liq. to liq. –55 to 125°C, 15 cycles	Frequency Output waveform		
MIL-STD-202	METHOD 105 COND. B.	Altitude, 3.44 inch Hg, 12 hrs	Frequency Output waveform		
MIL-STD-883	METHOD 1004	Moisture resist. with 5V applied 25-65°C, 90 to 100% RH, 10 cycles	Frequency Output waveform		
MIL-STD-202	METHOD 210 COND. A.	Resistance to Solder Heat Immersion @350°C 3.5 sec	Frequency Output waveform		
C. Subgroup 3 - 4 pcs. (One half of Subgroup 1)					
Standard	Condition Storage Temp. No. Oper.	Description 24 hrs. @ -55°C 24 hrs. @ 125°C	End point measurement Frequency Output waveform		
MIL-STD-883	METHOD 1009 COND. A	Salt Atmosphere 24 hrs. @ 35°C .5-3.0% Solution	Frequency Output waveform Visual		

Fine Leak

Gross Leak

SS# Rev. M5500 B



Unless customer-specific terms and conditions are signed by an officer of MF Electronics, the sale of this and all MF Electronics products are subject to terms and conditions set forth at www.mfelectronics.com/terms

Qs <5 x 10<sup>-</sup> 8

Visual in 125°C

Detector fluid